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Application	on/Control No.	Applicant(s)/Paten Reexamination	t under
10/601,4	99	NAVADA ET AL.	
Examiner	•	Art Unit	
Harold K	im	2182	

SEARCHED			
Class	Subclass	Date	Examiner
710	53, 52, 56, 57	11/13/2005	нк
711	154, 155	11/21/2005	НК
711	165, 109	11/21/2005	НК
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
710	53, 52	11/13/2005	нк
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
USPAT, USPGPUB, JPO, EPO, IEEE, NPL, PLUS, see attached search note, inventor search on eDan	11/13/2005	нк	
Search consulted with Primary Chris Shin, and Ilwoo Park in AU2182 and Primary Hong Kim in AU2185	11/21/2005	нк	

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